PTO/SB/08A (08-03)
Approved for use through 7/31/2006. OMB 0651-0031

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abstitute for form 1449A/PTO Complete if Known APPLICATION NUMBER 10/789,319 INFORMATION DISCLOSURE 02/27/2004 FILING DATE STATEMENT BY APPLICANT FIRST NAMED INVENTOR Xu et al. 1712 Group Art Unit (use as many sheets as necessary) Examiner Name Zimmer, Marc S. Sheet Attorney Docket Number P121-63-03 1

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Examiner Initials*	Cite No. <sup>1</sup>	Office	Foreign Pat		ment Kind Code <sup>5</sup> (if known)	Name of Patentee or Applic Cited Document	cant of	Date of Publication of Cited Document MM-DD-YYYY	Pages, Columns, Lines, Where Refevant Passages or Relevant	T <sup>6</sup>
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Signature

Date
Considered

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Substitute fo	or form 1449A/	PTO			ete if Known
INF	ORMATIO	N DISCLO	SURF	APPLICATION NUMBER	10/789,319
	ATEMENT			FILING DATE	02/27/2004
		D. 7 E		FIRST NAMED INVENTOR	Xu et al.
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Sheet	2	of	5	Attorney Docket Number	P121-63-03

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Examiner Initials*	Cite No.1	Foreign Patent Document  Office Number (if known)		Name of Patentee or Cited Docum		Date of Publication of Cited Document MM-DD-YYYY	Pages, Columns, Unes, Where Relevant Passages or Relevant Figures Appear	T°	
1	B19	4,617,238		Crivo	llo et al.	10/14/19		***************************************	
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	B20	6,580,172	B2	Mano	cini et al.	6/17/200	3		
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		_		Group Art Unit	1712		
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Sheet	3	of	5	Attorney Docket Number	P121-63-03		

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INFO	RMATION	DISCLO	SURE	APPLICATION NUMBER	10/789,319		
STA	TEMENT B	Y APPL	ICANT	FILING DATE	02/27/2004 Xu et al.		
				FIRST NAMED INVENTOR			
(use	e as many sheets	as necessar	Y)	Group Art Unit	1712		
Sheet	4	of	5	Examiner Name	Zimmer, Marc S.		
	<del></del>	<del></del>		Attorney Docket Number	P121-63-03		

OTHER PRIOR ART - NON PATENT LITERATURE DOCUMENTS

Examiner Initials*	Cite No.	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T <sup>2</sup>
m	B38	Chou et al., Nanoimprint Lithography, Journal of Vacuum Science Technology B 14(16), pp. 4129-4133, 11/1/1996	
1	B39	Colburn et al., Development and Advantages of Step-and-Flash Lithography, Solid State Technology, 7/1/2001	
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<sup>&</sup>lt;sup>1</sup> Applicant's unique citation designation number (optional). <sup>2</sup> Applicant is to place a check mark here if English language Translation is attached. This collection of information is required by 37 CFR 1.97 and 1.98. The information is required to obtain or retain a benefit by the public which is to file (and by the USPTO to process) an application. Confidentiality is governed by 35 U.S.C. 122 and 37 CFR 1.14. This collection is estimated to take 2 hours to complete, including gathering, preparing, and submitting the completed application form to the USPTO. Time will vary depending on the individual case. Any comments on the amount of time you require to complete this form and/or suggestions for reducing this burden, should be sent to the Chief Information Officer, U.S. Patent and Trademark Office, P.O. Box 1450, Alexandria, VA 22313-1450. DO NOT SEND FEES OR COMPLETED FORMS TO THIS ADDRESS. SEND TO: Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450.

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				FIRST NAMED INVENTOR	Xu et al.		
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		L		Attorney Docket Number	P121-63-03		

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my	B47	Yao et al., Structural, Mechanical and Hydrophobic Properties of Fluorine-Doped Diamond-Like Carbon Films Synthesized by Plasma Immersion Ion Implantation and Deposition (PIII-D), Applied Surface Science 230; pp. 172-178, 4/17/2004	
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Examiner Signature	mare lynner	Date Considered	6/2/05	
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## INFORMATION DISCLOSURE STATEMENT BY APPLICANT

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Sheet	1	of	2	

Complete if Known						
APPLICATION NUMBER   10/789,319						
FILING DATE	02/27/2004					
FIRST NAMED INVENTOR	Xu et al.					
Group Art Unit	1712					
Examiner Name	Zimmer, Marc S.					
Attorney Docket Number	P121-63-03					

		U.S. Patent	Document	U.S. PATENT DOCUMEN	<del>,                                      </del>	Pages, Columns, Lines,
Examiner nitials*	Cite No.1	Number	Kind Code <sup>2</sup> (# known)	Name of Patentee or Applicant of Cited Document	Date of Publication of Cited Document MM-DD-YYYY	Where Relevant Passages or Relevant Figures Appear
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1	C2	6,468,896	B2 .	Rohr et al.	10/22/2002	
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mx	C4	5,737,064		Inoue et al.	04/07/1998	
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	<del></del>	<u> </u>		Attorney Docket Number	P121-63-03		

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ms	C5	Data Sheet for MAK (Methyl n-Amyl Ketone), www.sp-chem.com/fine_e, 1/1/2003	
<del></del>	C8	Data Sheet for gamma-Glycidoxypropyltrimethoxysilane, www.powerchemical.net/3100.htm, 12/5/2003	
	C7	Silicon or Silica, www.mii.org/Minerals/photosil, 3/31/2005	
	C8	Electronic Devices and Circuits, people.deas.harvard.edu/~jones/es154/lectures/lecture_2/materials/materials.html, 3/31/2005	
	C9	Data Sheet for Cymel 303ULF, www.cytec.com, 12:00:00 AM	
	C10	Data Sheet for Cycat 4040, www.cytec.com, 12:00:00 AM	
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	C12	Data Sheet for p-Toluenesulfonic Acid, NIOSH Manual of Analytical Methods (NMAM), Fourth Edition, 12:00:00 AM	
	C13	Data Sheet for Dow Corning Z-6018, , 12:00:00 AM	
ms	C14	Data Sheet for Methyl Amyl Ketone, www.arb.ca.gov/db/solvents/solvent_pages/Ketones-HTML/methyl_amyl.htm, 3/31/2005	
Examiner Signature		Date Considered Class	

Examiner Signature	mare limes	Date Considered	4/1/05	
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# **ELECTRONIC INFORMATION DISCLOSURE STATEMENT**

Electronic Version v18 Stylesheet Version v18.0

Title of Invention

COMPOSITION FOR AN ETCHING MASK COMPRISING A SILICON-CONTAINING MATERIAL

**Application Number:** 

10/789319

\*10/789319\*

Confirmation Number:

9202

First Named Applicant:

Frank Xu

Attorney Docket Number: P121-63-03

Art Unit:

1712

Examiner:

Marc S. Zimmer

Search string:

(5737064).pn.

### **US Patent Documents**

Note: Applicant is not required to submit a paper copy of cited US Patent Documents

init	Cite.No.	Patent No.	Date	Patentee	Kind	Class	Subclass
m/	1	5737064	1998-04-07	Inoue et al.			

## Signature

Examiner Name	Date
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				U.S. PATENT DOCUMEN	TS	
Examiner Initials*	Cite No.'	U.S. Patent D	locument Kind Code <sup>z</sup> (if known)	Name of Patentee or Applicant of Cited Document	Date of Publication of Cited Document MM-DD-YYYY	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
10 C	A1	3,527,062		Belinski et al.	09-08-1970	
10	A2	3,783,520		King	01-08-1974	
	A3	3,807,027		Heisler	04-30-1974	
$\neg \vdash$	A4	3,807,029		Troeger	04-30-1974	
	A5	3,811,665		Seelig	05-21-1974	
7	A6	4,062,600		Wyse	12-13-1977	
$\neg$	A7	4,070,116		Frosch et al.	01-24-1978	
	A8	4,098,001		Watson	07-04-1978	
	A9	4,119,688		Hiraoka	10-10-1978	
T	A10	4,155,169		Drake et al.	05-22-1979	
	A11	4,201,800		Alcom et al	05-06-1980	
	A12	4,202,107		Watson	05-13-1980	
	A13	4,267,212		Sakawaki	05-12-1981	
	A14	4,326,805		Feldman et al.	04-27-1982	, —— <u>—</u>
	A15	4,337,579		De Fazio	07-06-1982	
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	A19	4,440,804		Milgram	04-03-1984	
	A20	4,451,507		Beltz et al.	05-29-1984	
	A21	4,507,331		Hiraoka	03-26-1985	
	A22	4,544,572		Sandvig et al.	10-01-1985	
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	A25	4,600,309		Fay	07-15-1986	
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	A27	4,657,845		Frechet et al.	04-14-1987	
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ms	A34	4,763,886		Takei	08-16-1988	
Examine/ Signature		mare	Janne	1	Date Considered	6/2/05

<sup>\*</sup>EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

<sup>&</sup>lt;sup>1</sup>Unique citation designation number. <sup>2</sup>See attached Kinds of U.S. Patent Documents. <sup>3</sup>Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). <sup>4</sup>For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. <sup>5</sup>Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST. 16 if possible. <sup>8</sup>Applicant is to place a check mark here if English language Translation is attached.

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Substitute for	form 1449A/PT	·o		Comple	te if Known		
				Application Number	10/789,319		
INFOR	MATION	DISCLO	OSURE	Filing Date	02/27/2004		
STATEMENT BY APPLICANT				First Named Inventor	Xu et al.		
•				Group Art Unit	1712		
(use as many sheets as necessary)				Examiner Name	Zimmer, Marc S.		
Sheet	2	of	25	Attorney Docket Number	P121-63-03		

rammer	Cite	U.S. Patent Document	Name of Patentee or Applicant	Date of Publication of	Pages, Columns, Lines,
itials*	No.1	Kınd Code Number (if known)		Cited Document MM-DD-YYYY	Where Relevant Passages or Relevant Figures Appear
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	A36	4,808,511	Holmes.	02-28-1989	
	A37	4,826,943	Ito et al.	05-02-1989	
	A38	4,846,931	Gmitter et al.	07-11-1989	
	A39	4,848,179	Ubhayakar	07-18-1989	
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	A41	4,857,477	Kanamori	08-15-1989	
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	A44	4,891,303	Garza et al.	01-02-1990	
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	A52	4,964,145	Maldonado	10-16-1990	
	A53	4,964,945	Calhoun et al.	10-23-1990	
	A54	4,976,818	Hashimoto et al.	12-11-1990	
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Substitute for	r form: 1449A/PT	O		Complete if Known		
				Application Number	10/789,319	
INFOR	MATION	DISCL	OSURE	Filing Date	02/27/2004	
STATE	MENT B	Y APP	LICANT	First Named Inventor	Xu et al.	
				Group Art Unit	1712	
(us	e as many sheet	ts as neces	ssary)	Examiner Name	Zimmer, Marc S.	
Sheet	3	of	25	Attorney Docket Number	P121-63-03	

riner	Cite No.1	U.S. Patent Do	Kind Code <sup>2</sup> (il known)	Name of Patentee or Applicant of Cited Document	Oate of Publication of Cited Document MM-DD-YYYY	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
1/3/2	A69	5,155,749		DiMilia et al.	10-13-1992	
	A70	5,169,494		Hashimoto et al.	12-08-1992	
	A71	5,171,490		Fudim	12-15-1992	
	A72	5,173,393		Sezi et al.	12-22-1992	
	A73	5,179,863		Uchida et al.	01-19-1993	
	A74	5,198,326		Hashimoto et al.	03-30-1993	
	A75	5,204,739		Domenicali	04-20-1993	
	A76	5,206,983		Guckel et al.	05-04-1993	
	A77	5,212,147		Sheats	05-18-1993	
	A78	5,218,193		Miyatake	06-08-1993	
	A79	5,234,793		Sebald et al.	08-10-1993	
	A80	5,240,550		Boehnke et al.	08-31-1993	
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	A82	5,242,711		DeNatale et al.	09-07-1993	
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'IN X	A102	5,417,802		Obeng	05-23-1995	

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Substitute for	or form 1449A/PTC	)		Complete if Known		
				<b>Application Number</b>	10/789,319	
INFOR	RMATION E	DISC	LOSURE	Filing Date	02/27/2004	
STATI	EMENT BY	API	PLICANT	First Named Inventor	Xu et al.	
				Group Art Unit	1712	
(us	se as many sheets	as пес	essary)	Examiner Name	Zimmer, Marc S.	
Sheet	4	of	25	Attorney Docket Number	P121-63-03	

xaminer	Cite No.1	U.S. Patent Document	Name of Patentee or Applicant	Date of Publication of	Pages, Columns, Lines,
nitials*	Cité No.	Kind Code <sup>z</sup> Number (if known)	of Cited Document	Cited Document Atta-DD-YYYY	Where Refevant Passages or Refevant Figures Appear
mix	A103	5,421,981	Leader et al.	06-06-1995	
10	A104	5,422,295	CHOI et al.	06-06-1995	
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	A120	5,523,878	Wallace et al.	06-04-1996	
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Substitute	for form 1449A/P	TO		Complete if Known		
				Application Number	10/789,319	
INFO	<b>RMATION</b>	DISCI	LOSURE	Filing Date	02/27/2004	
STAT	STATEMENT BY APPLICANT			First Named Inventor	Xu et al.	
				Group Art Unit	1712	
(	use as many she	ets as nece	essary)	Examiner Name	Zimmer, Marc S.	
Sheet	5	of	25	Attorney Docket Number	P121-63-03	

			U.S. PATENT DOCUME	NTS	
Examiner Initials*	Cite No.1		d Code <sup>2</sup> Name of Patentee or Applicar (nown) of Cited Document	Date of Publication of Cited Document MM-DD-YYYY	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
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ĺ	A140	5,772,905	Chou	06-30-1998	
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	A145	5,804,474	Sakaki et al.	09-08-1998	
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1	A148	5,855,686	Rust	01-05-1999	
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	A153	5,888,650	Calhoun et al.	03-30-1999	
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N	A158	5,926,690	Toprac et al.	07-20-1999	
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1	A169	6,038,280	Rossiger et al.	03-14-2000	
MX	A170	6,039,897	Lochhead et al.	03-21-2000	
xamine Signature		mare Comm		Date Considered	6/2/05

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Substitute for	r form 1449A/P1	TO		Complete if Known		
				Application Number	10/789,319	
INFOR	MATION	DISCL	OSURE	Filing Date	02/27/2004	
STATE	EMENT B	Y APPI	LICANT	First Named Inventor Xu et al.		
				Group Art Unit	1712	
(us	e as many shee	ets as neces	sary)	Examiner Name	Zimmer, Marc S.	
Sheet	6	of	25	Attorney Docket Number	P121-63-03	

xaminer	Cite No.1	U.S. Patent Doo	ument	U.S. PATENT DOCUMENTS  Name of Patentee or Applicant	Date of Publication of	Pages, Columns, Lines,
nitials*	Cité No.	Number	Kind Code <sup>2</sup> (if known)	of Cited Document	Cited Document MM-DD-YYYY	Where Relevant Passages or Relevant Figures Appear
m	A171	6,046,056		Parce et al.	04-04-2000	
10	A172	6,051,345	<u> </u>	Huang	04-18-2000	
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	A186	6,168,845	B1	Fontana, Jr. et al.	01-02-2001	
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	A201	6,337,262	B1	Pradeep et al.	01-08-2002	
	A202	6,355,198	B1	Kim et al.	03-12-2002	
10	A203	6,361,831	B1	Sato et al.	03-26-2002	
m5	A204	6,383,928	B1	Eissa	05-07-2002	
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<sup>1</sup>Unique citation designation number. <sup>2</sup>See attached Kinds of U.S. Patent Documents. <sup>3</sup>Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). <sup>4</sup>For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. <sup>5</sup>Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST. 16 if possible. <sup>9</sup>Applicant is to place a check mark here if English language Translation is attached.

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Complete if Known Substitute for form 1449A/PTO 10/789,319 **Application Number** INFORMATION DISCLOSURE Filing Date 02/27/2004 STATEMENT BY APPLICANT **First Named Inventor** Xu et al. 1712 **Group Art Unit** (use as many sheets as necessary) **Examiner Name** Zimmer, Marc S. 25 P121-63-03 Sheet of Attorney Docket Number

Examiner nitials*	Cite No.1	U.S. Patent D	Kind Code <sup>2</sup> (if known)	Name of Patentee or Applicant of Cited Document	Date of Publication of Cited Document MM-DD-YYYY	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
mi	A205	6,387,783	B1	Furukawa et al.	05-14-2002	
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<sup>1</sup>Unique citation designation number. <sup>2</sup>See attached Kinds of U.S. Patent Documents. <sup>3</sup>Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). <sup>6</sup>For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. <sup>5</sup>Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST. 16 if possible. <sup>9</sup>Applicant is to place a check mark here if English language Translation is attached.

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Substitute fo	or form 1449A/P	ТО		Complete if Known		
				Application Number	10/789,319	
INFOR	RMATION	DISC	LOSURE	Filing Date	02/27/2004	
STATI	EMENT B	Y APF	PLICANT	First Named Inventor	Xu et al.	
				Group Art Unit	1712	
. (us	se as many she	ets as nece	essary)	Examiner Name	Zimmer, Marc S.	
Sheet	. 8	of	25	Attorney Docket Number	P121-63-03	

arriner luals*	Cite No.1	U.S. Patent Da	cument Kind Code <sup>2</sup> (# known)	Name of Patentee or Applicant of Cited Document	Date of Publication of Cited Document MM-DD-YYYY	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
my	A239	6,646,662	81	Nebashi et al.	11-11-2003	
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<sup>&</sup>lt;sup>1</sup>Unique citation designation number. <sup>2</sup>See attached Kinds of U.S. Patent Documents. <sup>3</sup>Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). <sup>4</sup>For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. <sup>5</sup>Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST. 16 if possible. <sup>6</sup>Applicant is to place a check mark here if English language Translation is attached.

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Substitute for	form 1449A/PT	0		Complete if Known		
				Application Number	10/789,319	
INFOR	MATION	DISCL	OSURE	Filing Date	02/27/2004	
STATE	MENT BY	Y APP	LICANT	First Named Inventor	Xu et al.	
				Group Art Unit	1712	
(us	e as many sheet	s as neces	sary)	Examiner Name	Zimmer, Marc S.	
Sheet	9	of	25	Attorney Docket Number	P121-63-03	

antner	Cite No.	U.S. Patent Do		Name of Patentee or Applicant	Date of Publication of	Pages, Columns, Lines,
nitials*	Gie Ro.	Number	Kind Code <sup>2</sup> (if known)	of Cited Document	Cited Document MM-DD-YYYY	Where Relevant Passages or Relevant Figures Appear
2	A273	2003/0205657	A1	Voisin	11-06-2003	
<i>"\</i>	A274	2003/0205658	A1	Voisin	11-06-2003	
	A275	2003/0215577	A1	Willson et al.	11-20-2003	
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	A303	2004/0146792	A1	Nimmakayala et al.	07-29-2004	
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11	A305	2004/0150129	A1	Hougham et al.	08-05-2004	
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xaminer Signature		Mari Jum	mls		Date Considered	64/05

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Substitut	e for form 1449A/PT	o		Complete if Known		
				Application Number	10/789,319	
INF	DRMATION	DISC	LOSURE	Filing Date	02/27/2004	
STA	TEMENT B	Y APF	PLICANT	First Named Inventor	Xu et al.	
				Group Art Unit	1712	
	(use as many shee	ts as nec	essary)	Examiner Name	Zimmer, Marc S.	
Sheet	10	of	25	Attorney Docket Number	P121-63-03	

_		U.S. Patent Do	cument		Date of Dublimation of	Pages, Columns, Lines,
Examiner Initials*	Cite No.1	Number	Kind Code <sup>2</sup> (if known)	Name of Patentee or Applicant of Cited Document	Date of Publication of Cited Document MM-DD-YYYY	Where Relevant Passages or Relevant Figures Appear
11/2	A307	2004/0168586	A1	Bailey et al.	09-02-2004	
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h e	A320	2004/0211754	A1	Sreenivasan	10-28-2004	
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Complete if Known Substitute for form 1449A/PTO 10/789,319 **Application Number** INFORMATION DISCLOSURE 02/27/2004 **Filing Date** STATEMENT BY APPLICANT **First Named Inventor** Xu et al. Group Art Unit 1712 (use as many sheets as necessary) **Examiner Name** Zimmer, Marc S. 25 P121-63-03 Sheet of **Attorney Docket Number** 

Examiner	Crin		Foreign Patent Occume	Kind Code <sup>5</sup>	Name of Patentee or Applicant of	Date of Publication of	Pages, Columns, Lines, Where Relevant	T
tnitlals*	Cite No.1	Office <sup>3</sup>	Number <sup>4</sup>	(if known)	Cited Document	Cited Document MM-DD-YYYY	Passages or Relevant Figures Appear	'
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	A335	JP	63-138730		Koji	06-10-1988		Ť
	A336	wo	00/21689	<u> </u>	Chou et al.	04-20-2000		†
	A337	wo	00/54107	T i	Willson et al.	09-14-2000		Ť
1	A338	wo	01/33232		Andeen et al.	05-10-2001		†
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	A340	wo	01/47003	A2	Steiner et al.	06-28-2001		✝
	A341	wo	01/53889		Ling et al.	07-26-2001		T
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	A349	wo	02/006902		Choil et al.	01-24-2002		
	A350	wo	02/008835		Choi et al.	01-31-2002		L
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1 1	A355	wo	2004/006120		Watts et al.	01-15-2004		
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<sup>&</sup>lt;sup>1</sup>Unique citation designation number. <sup>2</sup>See attached Kinds of U.S. Patent Documents. <sup>2</sup>Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). <sup>4</sup>For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. <sup>5</sup>Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST. 16 if possible. <sup>9</sup>Applicant is to place a check mark here if English language Translation is attached.

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Substitute for	r form 1449A/P	то		Complete if Known		
				Application Number	10/789,319	
INFOR	<b>MATION</b>	DISCL	OSURE	Filing Date	02/27/2004	
STATE	MENT B	Y APP	LICANT	First Named Inventor	Xu et al.	
				Group Art Unit	1712	
(use	e as many shee	ets as nece	ssary)	Examiner Name	Zimmer, Marc S.	
Sheet	12	of	25	Attorney Docket Number	P121-63-03	

					PATENT DOCUMENTS			
Examiner Initials*	Cite No.1	Office <sup>3</sup>	Fore:gn Patent Docur Number <sup>4</sup>	Kind Code <sup>5</sup> (if known)	Name of Patentee or Applicant of Cited Document	Date of Publication of Cited Document MM-DD-YYYY	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	۲
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	A365	wo	99/45753		Wikström	09-10-1999		1
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Substit	tute for form 1449B	/PTO		Compl	ete if Known
				Application Number	10/789,319
INF	ORMATION	DISC	LOSURE	Filing Date	02/27/2004
STA	ATEMENT E	BY APF	PLICANT	First Named Inventor	Xu et al.
				Group Art Unit	1712
	(use as many she	eets as nec	essary)	Examiner Name	Zimmer, Marc S.
Sheet	13	of	25	Attorney Docket Number	P121-63-03

OTHER P	RIOR ART -	NON PATENT LITERATURE DOCUMENTS	
Examiner Initials*	Cite No.	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T <sup>2</sup>
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	A369	Abstract of Japanese Patent 55-88332, April 14, 2004	
	A370	Abstract of Japanese Patent 57-7931, April 14, 2004	1
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Date Considered	6/2/05	
		Considered 6/2/05

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Substitu	ute for form 1449B/	PTO		Complete if Known		
				<b>Application Number</b>	10/789,319	
INFORMATION DISCLOSURE STATEMENT BY APPLICANT				Filing Date	02/27/2004	
				First Named Inventor	Xu et al.	
				Group Art Unit	1712	
(use as many sheets as necessary)			essary)	Examiner Name	Zimmer, Marc S.	
Sheet	14	of	25	Attorney Docket Number	P121-63-03	

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				Application Number	10/789,319	
INFO	RMATIO	N DISCI	LOSURE	Filing Date	02/27/2004	
STATEMENT BY APPLICANT				First Named Inventor	Xu et al.	
				Group Art Unit	1712	
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INF	ORMATION	I DISCI	LOSURE	Filing Date	02/27/2004
STA	TEMENT B	BY APF	PLICANT	First Named Inventor	Xu et al.
				Group Art Unit	1712
(use as many sheets as necessary)				Examiner Name	Zimmer, Marc S.
Sheet	16	of	25	Attorney Docket Number	P121-63-03

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				<b>Application Number</b>	10/789,319	
INF	ORMATION	N DISC	LOSURE	Filing Date	02/27/2004	
STATEMENT BY APPLICANT				First Named Inventor	Xu et al.	
				Group Art Unit	1712	
(use as many sheets as necessary)				Examiner Name	Zimmer, Marc S.	
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Examiner Signature	may Jumine	4	Date Considered	64105	

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				Application Number	10/789,319	
INFO	<b>PRMATION</b>	DISC	CLOSURE	Filing Date	02/27/2004	
STA	TEMENT E	BY AP	PLICANT	First Named Inventor	Xu et al.	
				Group Art Unit	1712	
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Sheet	18	of	25	Attorney Docket Number	P121-63-03	

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STA	ATEMENT B	Y AF	PPLICANT	First Named Inventor	Xu et al.
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Examiner Date	
Signature May Cons	dered 6/2/05

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Sheet	21	of·	25	Attorney Docket Number	P121-63-03	

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Examiner Initials*	Cite No.	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T <sup>2</sup>
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<sup>\*</sup>EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

<sup>&</sup>lt;sup>1</sup>Unique citation designation number. <sup>2</sup>Applicant is to place a check mark here if English language Translation is attached.

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Substitute	for form 1449B	B/PTO		Complete if Known		
				Application Number	10/789,319	
INFO	<b>RMATIO</b>	N DISCI	LOSURE	Filing Date	02/27/2004	
STATEMENT BY APPLICANT				First Named Inventor	Xu et al.	
•				Group Art Unit	1712	
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Sheet	22	of	25	Attorney Docket Number	P121-63-03	

OTHER PRIO	R ART - I	NON PATENT LITERATURE DOCUMENTS	
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Substitu	te for form 1449B	/PTO		. Complete if Known		
				Application Number	10/789,319	
INFO	DRMATION	I DISCI	LOSURE	Filing Date	02/27/2004	
STA	TEMENT	BY APP	LICANT	First Named Inventor	Xu et al.	
			•	Group Art Unit	1712	
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Sheet	23	of	25	Attomey Docket Number	P121-63-03	

OTHER PRIOR	R ART - N	NON PATENT LITERATURE DOCUMENTS	
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Examiner Signature	mu.	Summer	Date Considered	6465

<sup>\*</sup>EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

<sup>&</sup>lt;sup>1</sup>Unique citation designation number. <sup>2</sup>Applicant is to place a check mark here if English language Translation is attached.

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Substitu	ute for form 1449B	/PTO		Complete if Known		
				Application Number	10/789,319	
INF	ORMATION	I DISCI	LOSURE	Filing Date	02/27/2004	
STA	ATEMENT B	BY APP	LICANT	First Named Inventor	Xu et al.	
				Group Art Unit	1712	
(use as many sheets as necessary)				Examiner Name	Zimmer, Marc S.	
Sheet	24	of	25	Attorney Docket Number	P121-63-03	

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Examiner Signature Mall www.	Date Considered	6/2/05

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Substitute	for form 1449E	B/PTO		Complete if Known		
				Application Number	10/789,319	
INFORMATION DISCLOSURE STATEMENT BY APPLICANT				Filing Date	02/27/2004	
				First Named Inventor	Xu et al.	
				Group Art Unit	1712	
(use as many sheets as necessary)				Examiner Name	Zimmer, Marc S.	
Sheet	25	of	25	Attorney Docket Number	P121-63-03	

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# **ELECTRONIC INFORMATION DISCLOSURE STATEMENT**

### Electronic Version v18

Stylesheet Version v18.0

Title of Invention

COMPOSITION FOR AN ETCHING MASK COMPRISING A SILICON-CONTAINING MATERIAL

**Application Number:** 

10/789319

9202

Confirmation Number:

First Named Applicant:

Frank Xu

Attorney Docket Number:

P121-63-03

Art Unit:

1712

Examiner:

Marc S. Zimmer

Search string:

( 6468642 or 5542978 or 5837314 or 6565776 or 6503914 or 6649272 or 6204343

or 4614667 or 3810874 or 6737489 or 6721529 or 6664306 or 6790905 or 6544594

or 6774183 or 6830819 or 6802870 or 5389696 ).pn

### **US Patent Documents**

Note: Applicant is not required to submit a paper copy of cited US Patent Documents

init	Cite.No.	Patent No.	Date	Patentee	Kind	Class	Subclass
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·/	2	5542978	1996-08-06	Kindt-Larsen et al.	***		
	3	5837314	1998-11-17	Beaton et al.			
	4	6565776	2003-05-20	Li et al.	, B1		
	5	6503914	2003-01-07	Benish et al.	B1	1	
	6	6649272	2003-11-18	Moore et al.	B2		
	7	6204343	2001-03-20	Barucha et al.	B1		
	8	4614667	1986-09-30	Larson et al.			\
	9	3810874	1974-05-14	Mitsch et al.			
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	12	6664306	2003-12-16	Gaddam et al.	B2		
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Signature

mar Jimmes

6/13/05